

1 / 1 2

FIG. 1

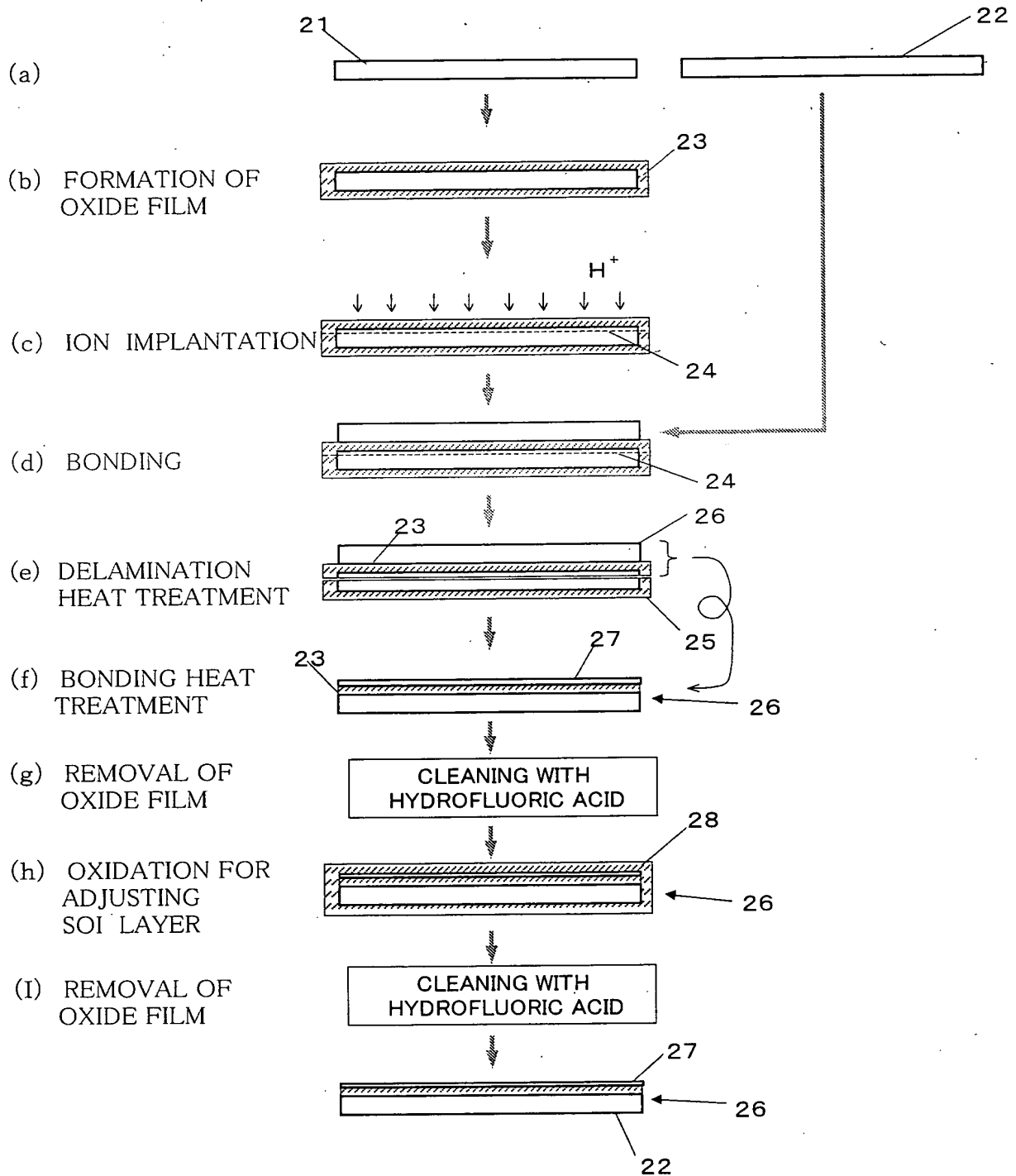
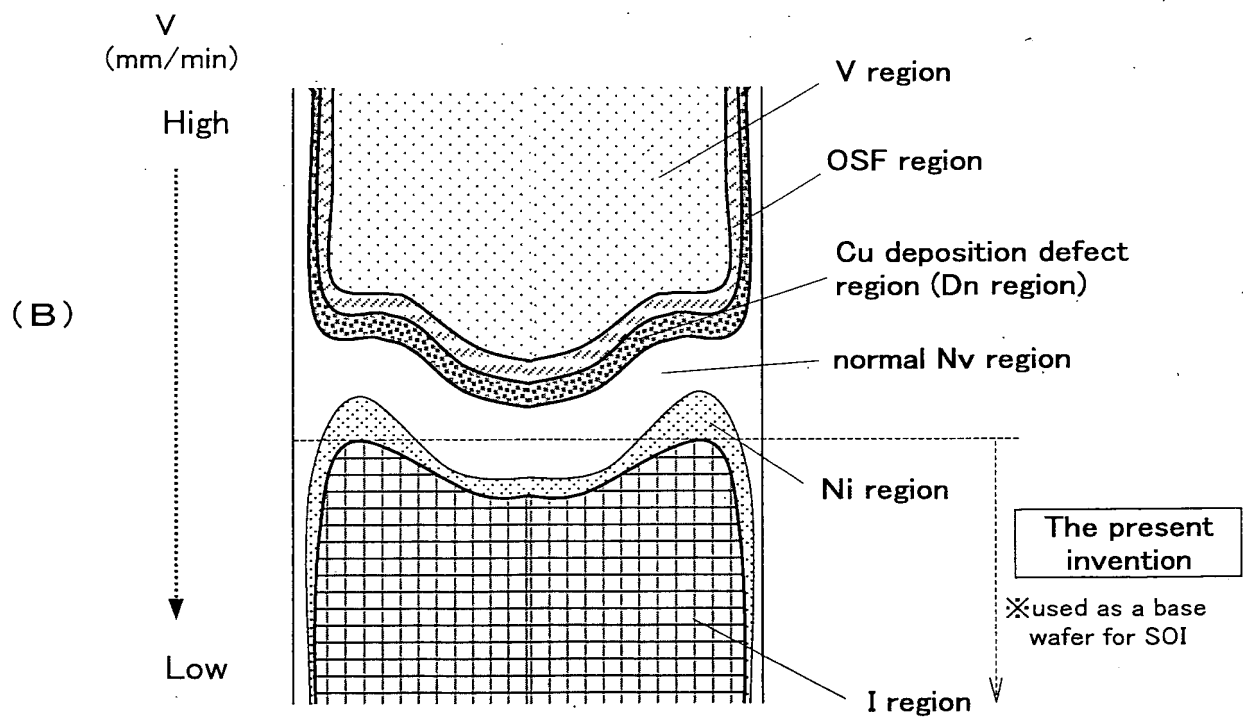
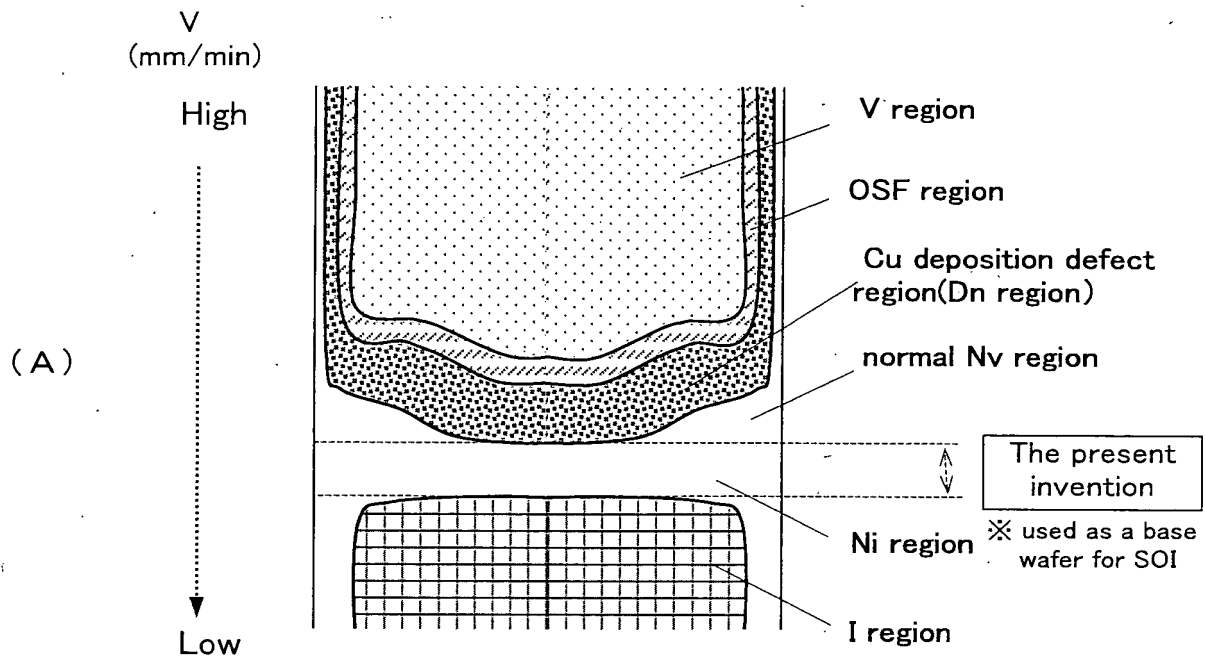


FIG. 2



10/542376

3 / 1 2

FIG. 3

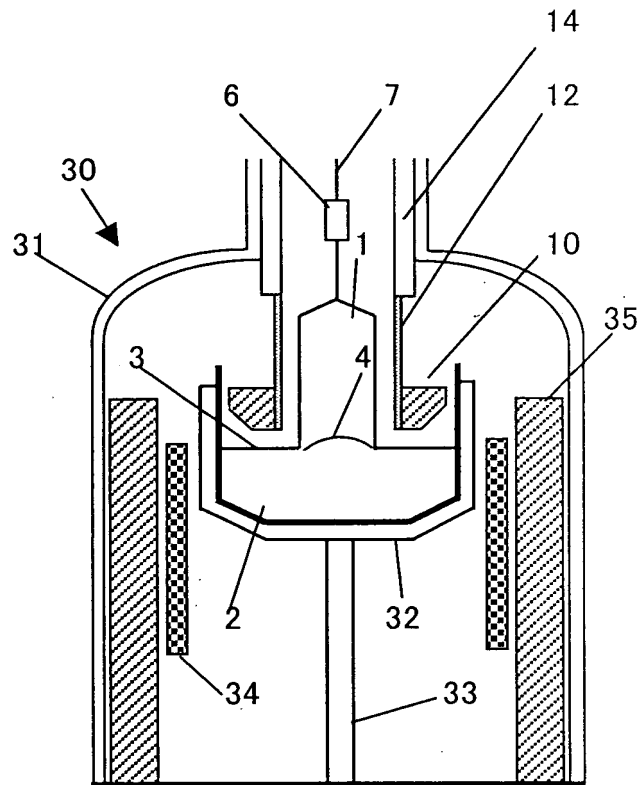


FIG. 4

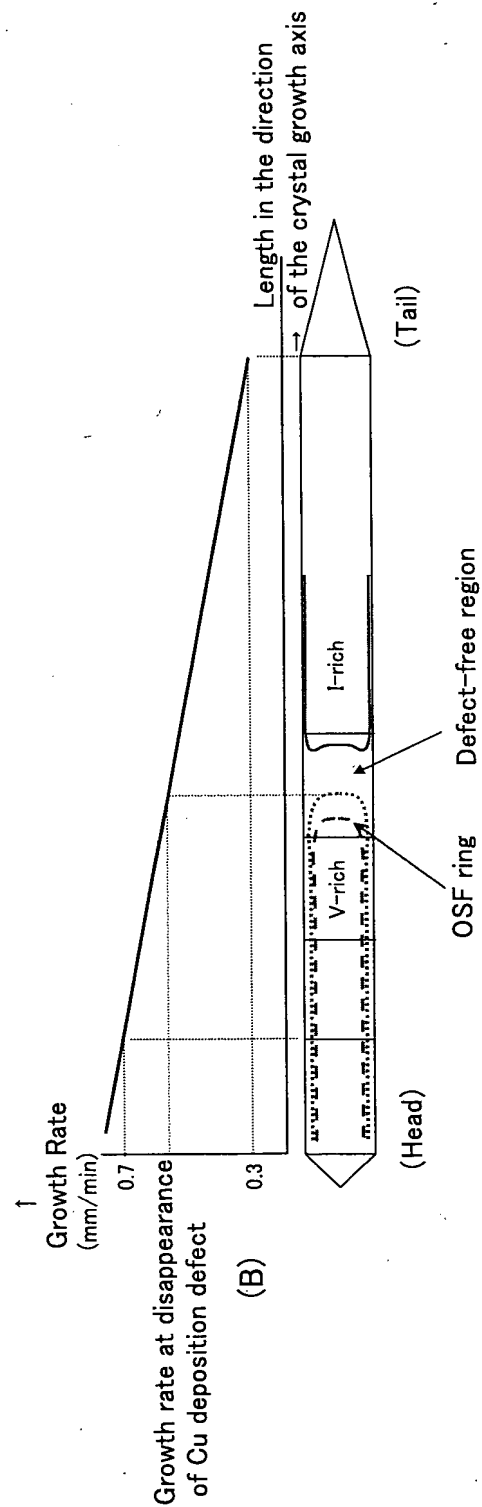
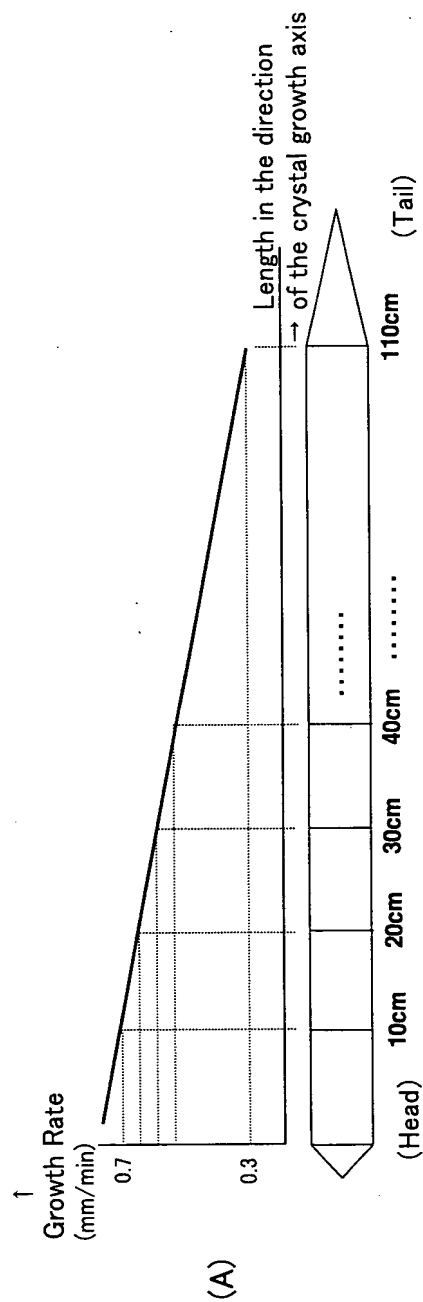


FIG. 5

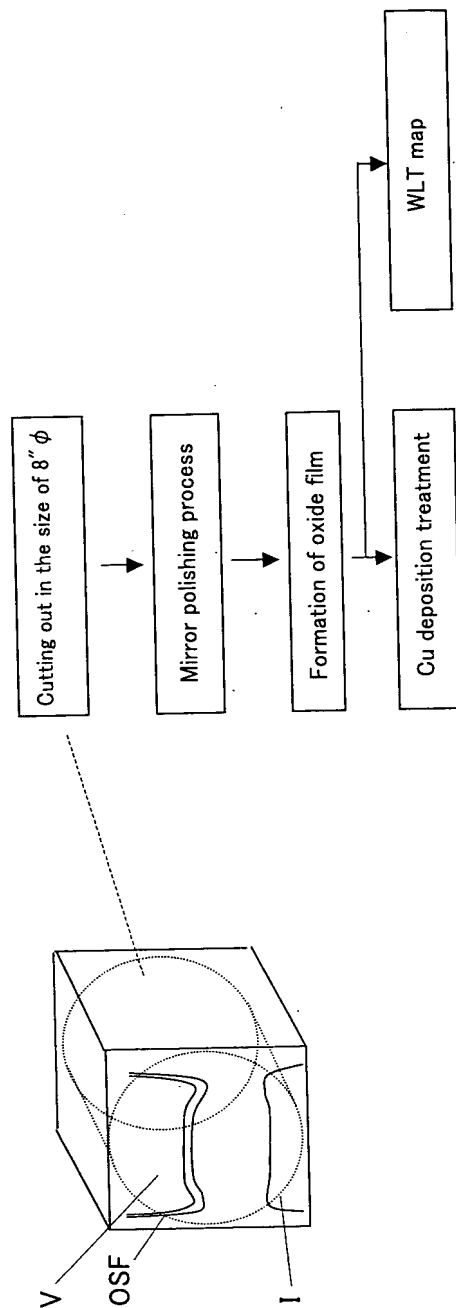


FIG. 6

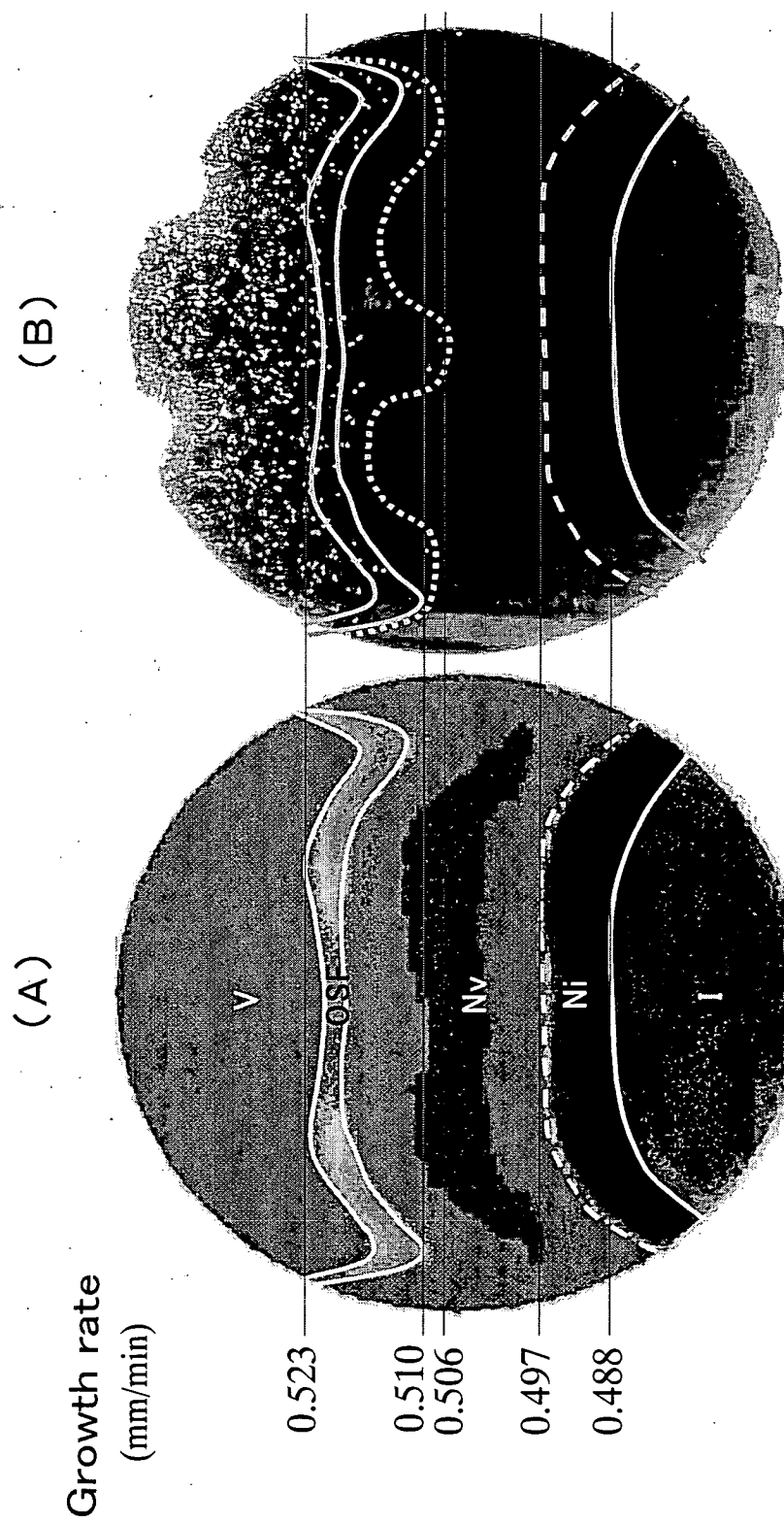


FIG. 7

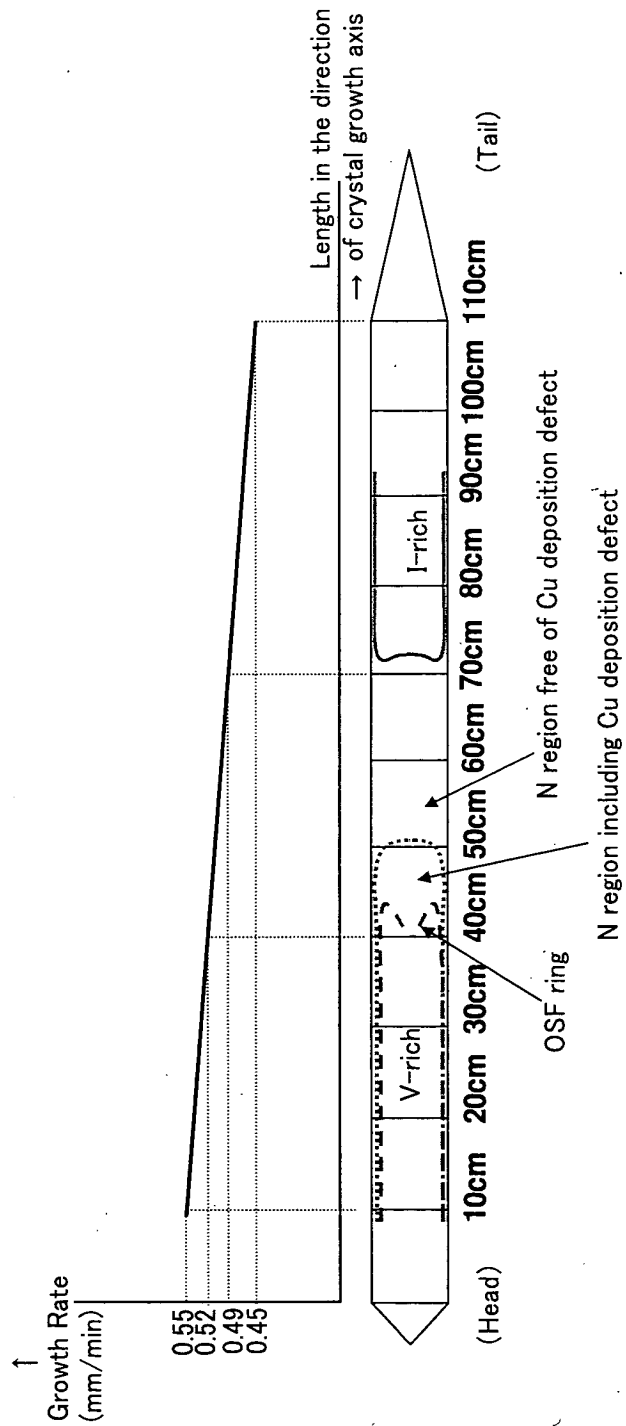


FIG. 8

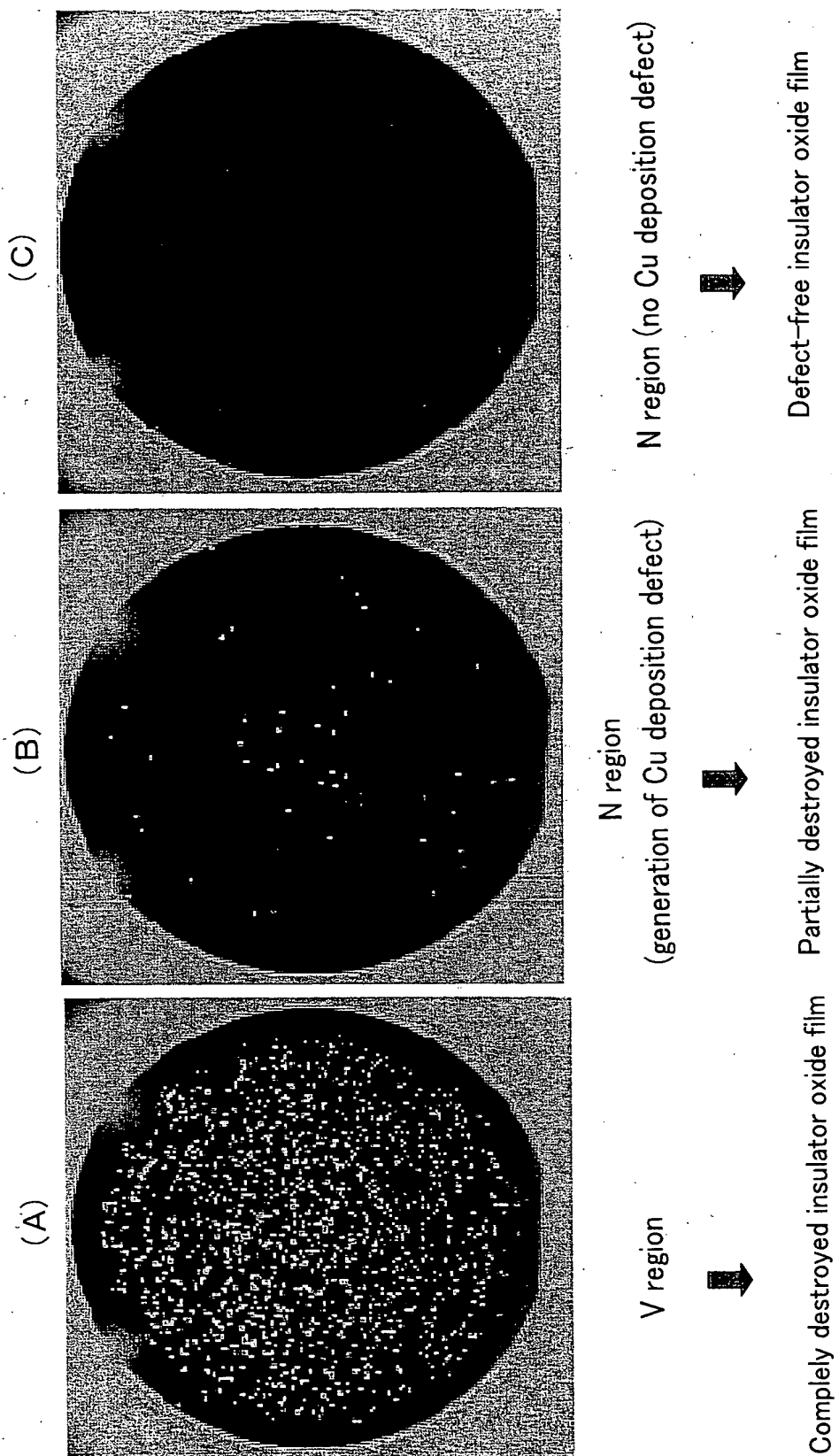
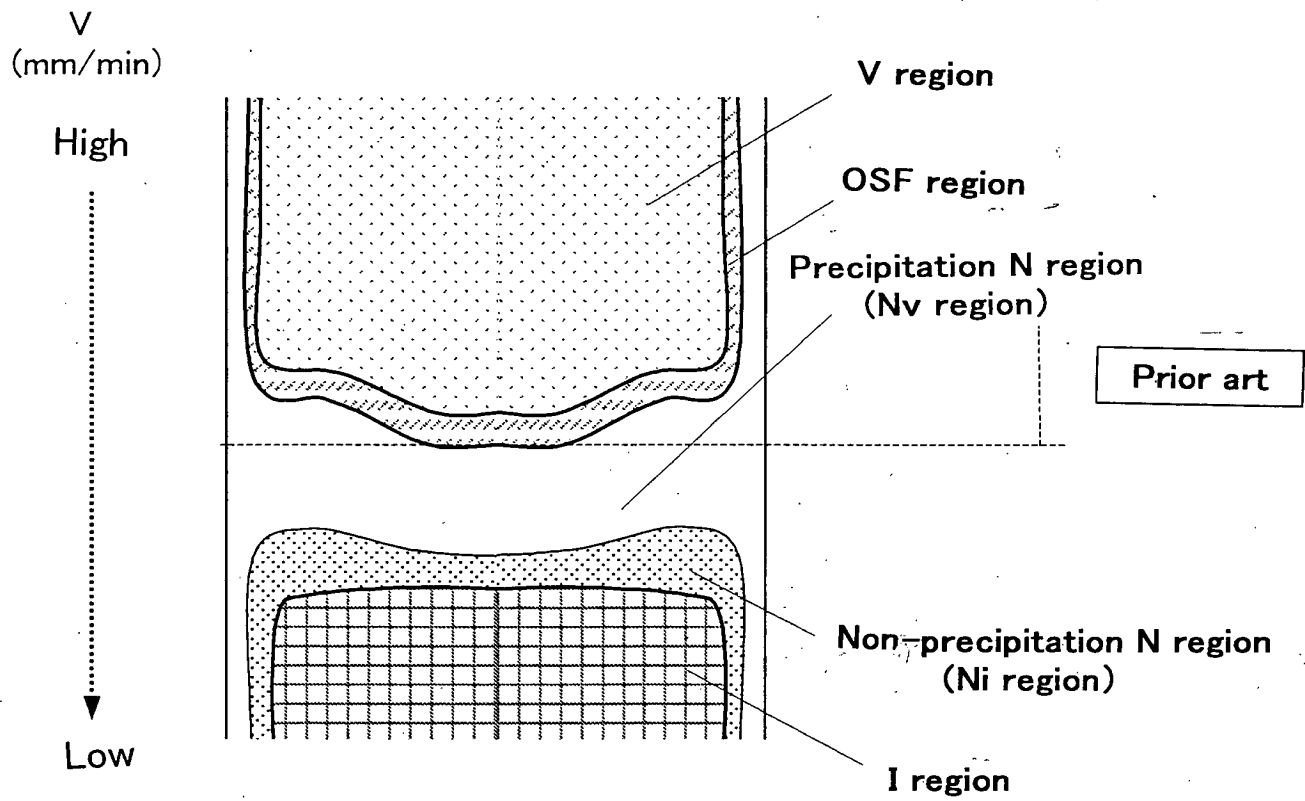




FIG. 9



10/542376

10/12

FIG. 10

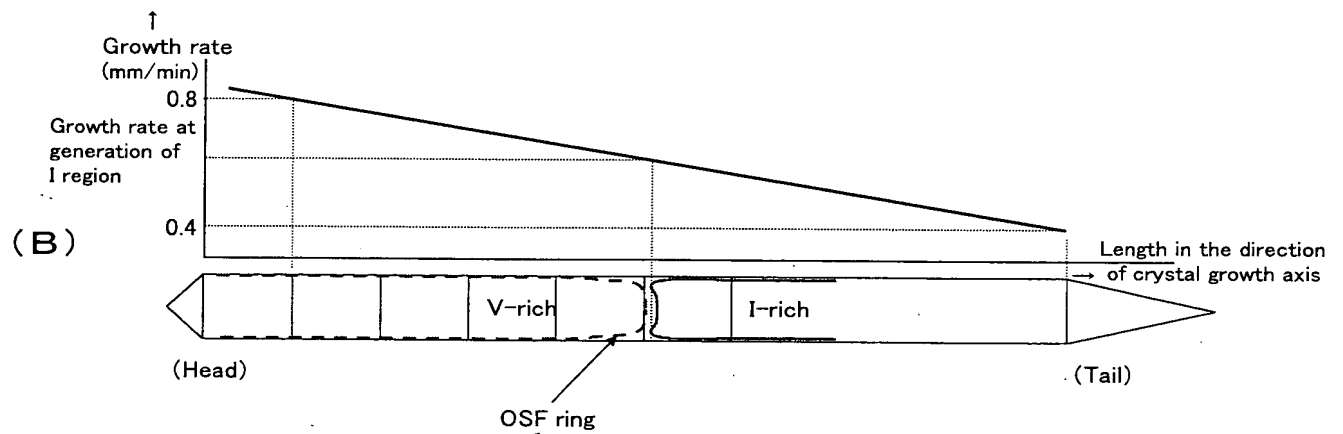
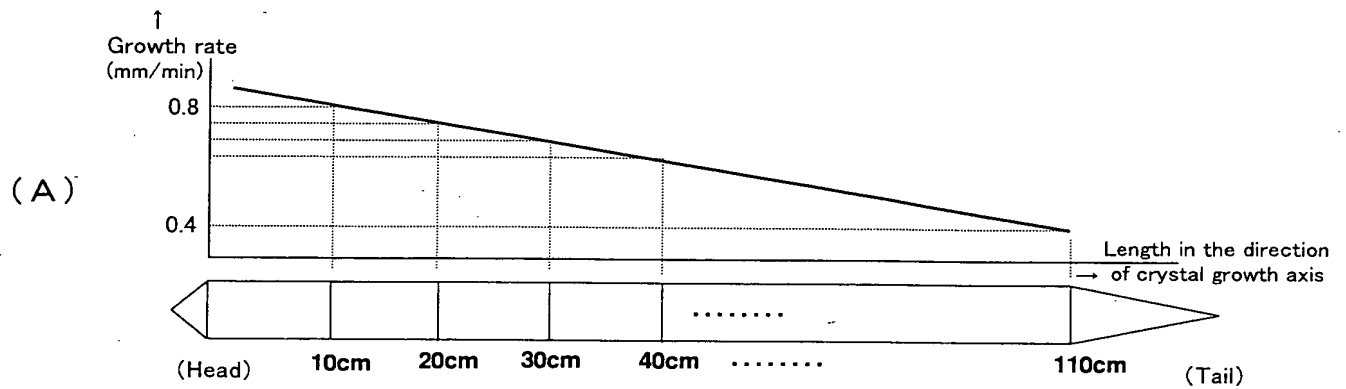


FIG. 11

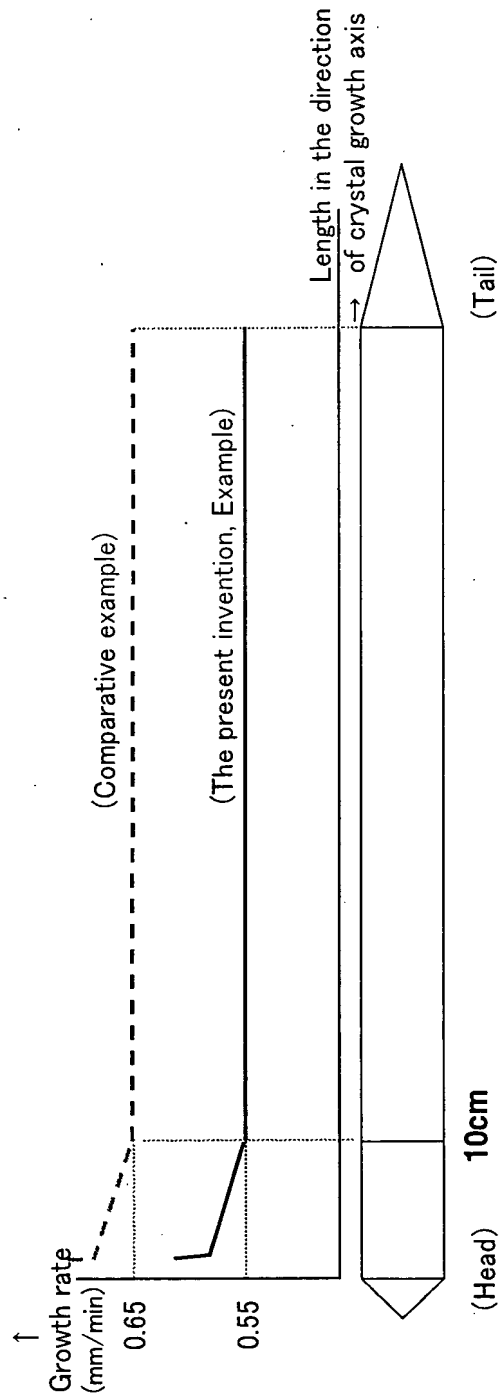
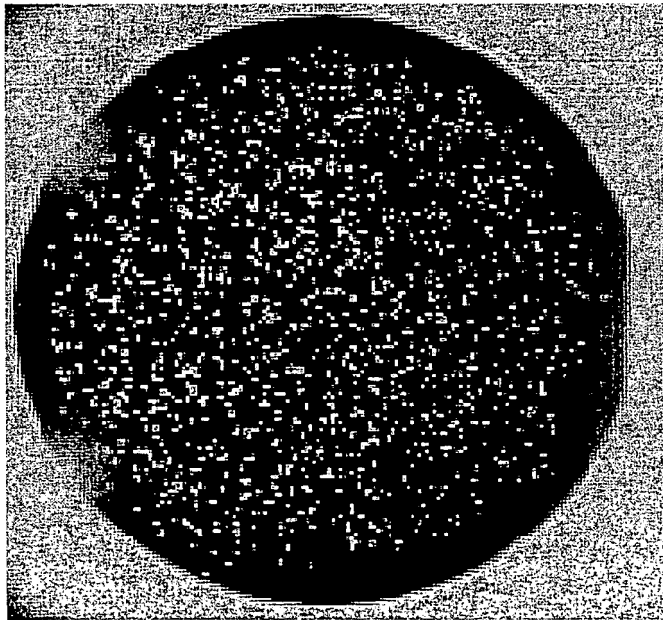


FIG. 12

(A)

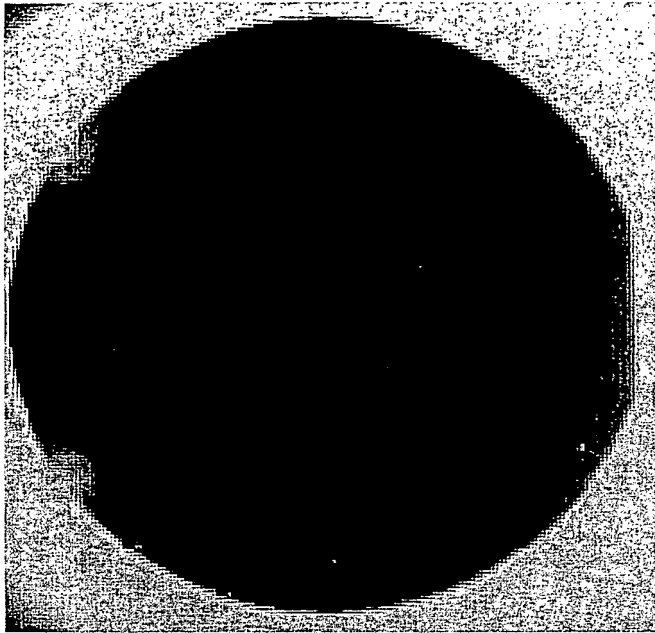


V region



Completely destroyed insulator oxide film

(B)



I region (no Cu deposition defect)



Defect-free insulator oxide film